



## ASSET LIST

# LOT 167: SEMICONDUCTOR MANUFACTURING TEST PATENTS FOR SALE

## 167号专利包：半导体制造测试专利待拍

Ocean Tomo Bid-Ask™ Market patent auction lot 167 consists of fifteen U.S. and international patents, as well as software source code and trademarks. The patents cover a system, software, method, test data and equipment for testing the integrated-circuit (IC) chip. The subject technology can reduce the scan test time which is significant in reduction of the manufacturing test cost. Further, the reduction of the scan test time is significant in the time-to-market of a product. The portfolio is applicable to a variety of industries such as foundry and integrated device manufacturer (“IDM”) companies, semiconductor automatic test equipment (“ATE”) companies, electronic design automation (“EDA”) software firms, outsourced semiconductor assembly and testing (“OSAT”) companies, fabless companies, etc. The subject assets for sale could help the acquirer build up a ready-to-use patent portfolio for strategic purposes.

Ocean Tomo Bid-Ask™市场167号拍卖专利包包括十五项美国和国际专利，以及软件源代码和商标。这些专利涵盖了用于测试集成电路（IC）芯片的系统、软件、方法、测试数据和设备。本发明可以缩短扫描测试的时间和功耗，对降低制造测试成本具有重要意义。此外，扫描测试时间的缩短对于产品快速上市至关重要。该专利包适用于广泛的行业领域，例如代工和集成设备制造商（“IDM”）、半导体自动测试设备（“ATE”）公司、电子设计自动化（“EDA”）软件公司、外包半导体（产品）封装和测试（“OSAT”）企业、无晶圆厂模式的半导体公司等。该待售资产可以帮助收购方快速建立符合其战略目的的即用型专利资产。

For further information or to bid on this lot, please email [Bid-Ask@OceanTomo.com](mailto:Bid-Ask@OceanTomo.com).  
竞拍该专利包或详询更多信息，欢迎联系 [Bid-Ask@OceanTomo.com](mailto:Bid-Ask@OceanTomo.com).

NO.	PUBLICATION NO.	PATENT TITLE	PRIMARY IP CLASS	PRIORITY DATE	FILE DATE	ISSUE/PUBLICATION DATE	NO. OF FORWARD CITATIONS
序号	公开号	专利名称	IPC主分类号	优先权日	申请日	公开日	前引数量
1	US10088520 B1	Apparatus, method, and system for testing ic chip  集成电路芯片的测试装置、方法和系统	G01R03102000	10/27/15	1/13/18	10/2/18	
2	US10228419 B2	Apparatus, method, and system for testing ic chip  集成电路芯片的测试装置、方法和系统	G01R03128000	4/28/16	10/26/17	3/12/19	
3	US9945904 B1	Apparatus, method, and system for testing ic chip  集成电路芯片的测试装置、方法和系统	G01R03102000	10/27/15	11/11/17	4/17/18	
4	KR101618822 B1	Method for minimizing scan test time and apparatus therefor  最小化扫描测试时间的方法及其装置	G01R03131830	10/29/14	11/17/14	5/18/16	
5	KR101618821 B1	Method for minimizing scan test time and apparatus therefor  最小化扫描测试时间的方法及其装置	G01R03131830	11/17/14	11/17/14	5/18/16	
6	KR101848480 B1	Apparatus, method, and system for testing integrated circuit chip  一种集成电路芯片的测试装置、方法和系统	G01R03131850	4/28/16	4/26/17	4/13/18	
7	KR101923142 B1	Apparatus, method, and system for testing integrated circuit chip  一种集成电路芯片的测试装置、方法和系统	G01R03131850	10/29/14	1/9/18	11/28/18	
8	KR102373560 B1	Method and apparatus for generating search-data for searching optimal shift frequency of test data for ic chip scan test  用于产生用于搜索用于集成芯片扫描测试的测试数据的最佳移位频率的搜索数据的方法和装置	G01R03131850	8/18/21	8/18/21	3/14/22	
9	KR101649708 B1	Method for minimizing burn-in test time and apparatus therefor  最小化老化测试时间的方法及其装置	G01R03126000	10/29/14	11/27/14	8/23/16	
10	KR 1020220026307 (Application Number)	Method and apparatus for generating search-data for searching optimal shift frequency of test data for IC chip scan test  用于搜索集成芯片扫描测试的测试数据的最佳移位频率的搜索数据生成方法和装置	G01R03131850	8/18/21	2/28/22	N/A	
11	KR 1020220074504 (Application Number)	Apparatus, method, and system for testing integrated circuit chip  一种集成电路芯片的测试装置、方法和系统	G01R03131850	6/19/22	6/19/22	N/A	
12	CN109061432 B	Ic chip testing apparatus, method and system, and computer-readable storage medium  集成芯片测试装置、方法和系统以及计算机可读存储介质	G01R03128000	10/29/14	3/20/18	9/4/20	
13	JP 06209299 B1	Ic chip test apparatus, ic chip test method, and ic chip test system  集成电路芯片的测试装置、方法和系统	G01R03131700	4/28/16	4/26/17	10/4/17	
14	TWI629493 B	Apparatus, method, and system for testing ic chip  集成电路芯片的测试装置、方法和系统	G01R03131850	10/29/14	4/27/17	7/11/18	
15	SG11201808983Y A	Apparatus, method, and system for testing ic chip  集成电路芯片的测试装置、方法和系统	G01R03131850	4/28/16	4/27/17	11/29/18	
16	Software source code		N/A	N/A	N/A	N/A	
17	KR 40-1327602	Trademark - Veloscan	N/A	N/A	2/14/18	N/A	
18	US 5688928	Trademark - Veloscan	N/A	N/A	2/14/18	3/5/19	